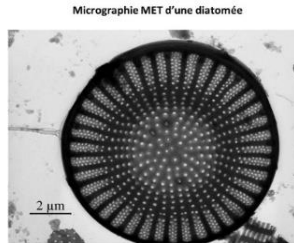
INSTITUT JEAN LAMOUR

cnrs UNIVERSITÉ DE LORRAINE

Our services

Microscopy (SEM, SEM-FIB, TEM), Castaing Microprobe

Micrographie MET d'une diatomée



Dr J. Ghanbaja (IJL)

YOUR NEEDS

- Material characterization tools using different structure and/or microstructure analysis techniques

RELATED SKILLS

- Structural analysis by X-ray diffraction

OUR SOLUTIONS

- Characterization of materials by different electron microscopy and microanalysis techniques (TEM, SEM, microprobe and SIMS)
- Preparation of thin slides using focused ion beam (FIB)
- Characterization of materials at different scales ranging from a few tenths of a nanometre to a few hundred micrometres depending on the techniques used
- Qualitative and quantitative analyses of the composition of materials,
- 2 Transmission Electron Microscopes
- 2 Scanning Electron Microscopes
- 1 Scanning Electron Microscope with focused ion beam
- 1 Electronic Microprobe from Castaing

OUR REFERENCES

KEYWORDS

SEM, SEM-FIB, TEM, Microscopy,

CONTACT

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